



<b>Title of Change:</b>	NCP1124/6/9 Datasheet Update - Tcs (LEB) Upper Limit Change from 400 nS to 420 nS.					
<b>Proposed First Ship date:</b>	14 Jul 2020 or earlier if approved by customer					
<b>Contact Information:</b>	Contact your local ON Semiconductor Sales Office or <a href="mailto:Marquita.Jones@onsemi.com">Marquita.Jones@onsemi.com</a>					
<b>PCN Samples Contact:</b>	Contact your local ON Semiconductor Sales Office or <a href="mailto:PCN.samples@onsemi.com">PCN.samples@onsemi.com</a> Sample requests are to be submitted no later than 30 days from the date of first notification, Initial PCN or Final PCN, for this change. Samples delivery timing will be subject to request date, sample quantity and special customer packing/label requirements.					
<b>Additional Reliability Data:</b>	N/A					
<b>Type of Notification:</b>	This is a Final Product/Process Change Notification (FPCN) sent to customers. FPCNs are issued 90 days prior to implementation of the change. ON Semiconductor will consider this change accepted, unless an inquiry is made in writing within 30 days of delivery of this notice. To do so, contact <a href="mailto:PCN.Support@onsemi.com">PCN.Support@onsemi.com</a>					
<b>Marking of Parts/ Traceability of Change:</b>	Product marked with date code 2029 (YYWW) or later may be tested per the updated Tcs (LEB) upper limit. The trace code marking on line 3 is of the form (YYWW)G where YY = Year of Production, Last Two Numbers and WW = Work Week Number					
<b>Change Category:</b>	Datasheet Update, Test Change					
<b>Change Sub-Category(s):</b>	Product specific change					
<b>Sites Affected:</b>						
<b>ON Semiconductor Sites</b>				<b>External Foundry/Subcon Sites</b>		
ON Semiconductor Carmona, Philippines				None		
<b>Description and Purpose:</b>						
Based on the results of additional characterization data, we are widening the upper limit for Tcs (LEB) for NCP1124/6/9 Datasheet.						
This specification change is not the result of a design or manufacturing process change.						
The new specification reflects a guard banded limit to the new comprehensive distribution, enabling ON Semiconductor to maintain its high quality standards.						
<b>Reliability Data Summary:</b>						
N/A						
<b>Electrical Characteristics Summary:</b>						
<b>BEFORE</b>						
<b>Characteristics</b>	<b>Conditions</b>	<b>Symbol</b>	<b>Min</b>	<b>Typ</b>	<b>Max</b>	<b>Unit</b>
Cycle by Cycle Leading Edge Blanking Duration		$t_{CS(LEB)}$	–	320	400	ns
<b>AFTER</b>						
<b>Characteristics</b>	<b>Conditions</b>	<b>Symbol</b>	<b>Min</b>	<b>Typ</b>	<b>Max</b>	<b>Unit</b>
Cycle by Cycle Leading Edge Blanking Duration		$t_{CS(LEB)}$	–	320	420	ns

**List of Affected Parts:**

**Note:** Only the standard (off the shelf) part numbers are listed in the parts list. Any custom parts affected by this PCN are shown in the customer specific PCN addendum in the PCN email notification, or on the **PCN Customized Portal**.

Part Number	Qualification Vehicle
NCP1124AP65G	NCP1129BP100G
NCP1124BP65G	NCP1129BP100G
NCP1124AP100G	NCP1129BP100G
NCP1124BP100G	NCP1129BP100G
NCP1126AP65G	NCP1129BP100G
NCP1126BP65G	NCP1129BP100G
NCP1126AP100G	NCP1129BP100G
NCP1126BP100G	NCP1129BP100G
NCP1129AP65G	NCP1129BP100G
NCP1129BP65G	NCP1129BP100G
NCP1129AP100G	NCP1129BP100G
NCP1129BP100G	NCP1129BP100G